


<b>Search Notes</b>  	<b>Application/Control No.</b>  10661503	<b>Applicant(s)/Patent Under Reexamination</b>  HIKAWA ET AL.
	<b>Examiner</b>  PHILIP C LEE	<b>Art Unit</b>  2152

SEARCHED			
Class	Subclass	Date	Examiner
709	106,224	7/18/08	/pl/
707	10	7/18/08	/pl/
717	102	7/18/08	/pl/

SEARCH NOTES		
Search Notes	Date	Examiner
keywords search in EAST	7/18/08	/pl/
keywords search in 709/106,224; 707/10; 717/102 in EAST	7/18/08	/pl/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner